

METHOD AND SYSTEM FOR IDENTIFYING AND  
LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

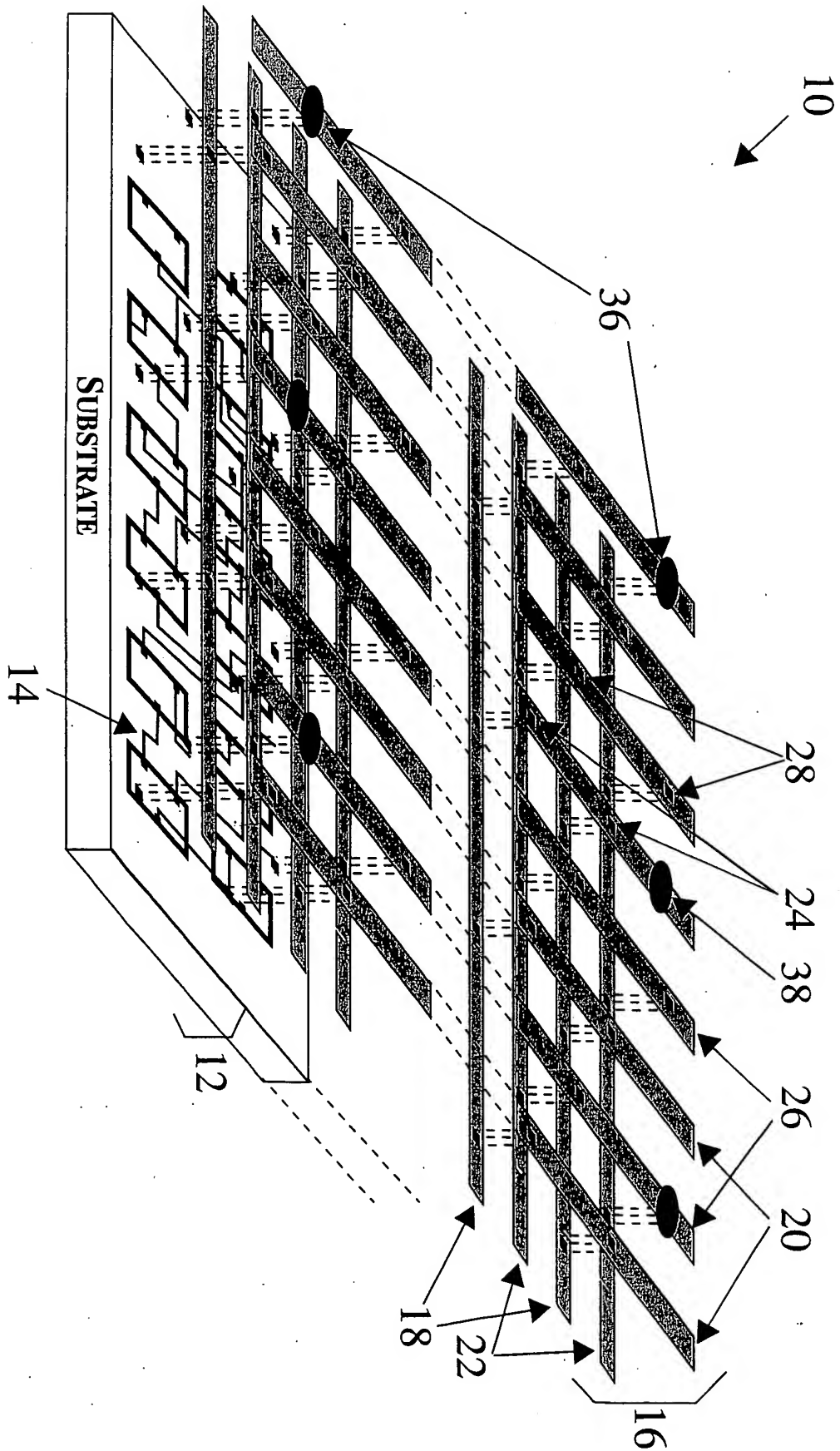


Figure 1

METHOD AND SYSTEM FOR IDENTIFYING AND  
LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

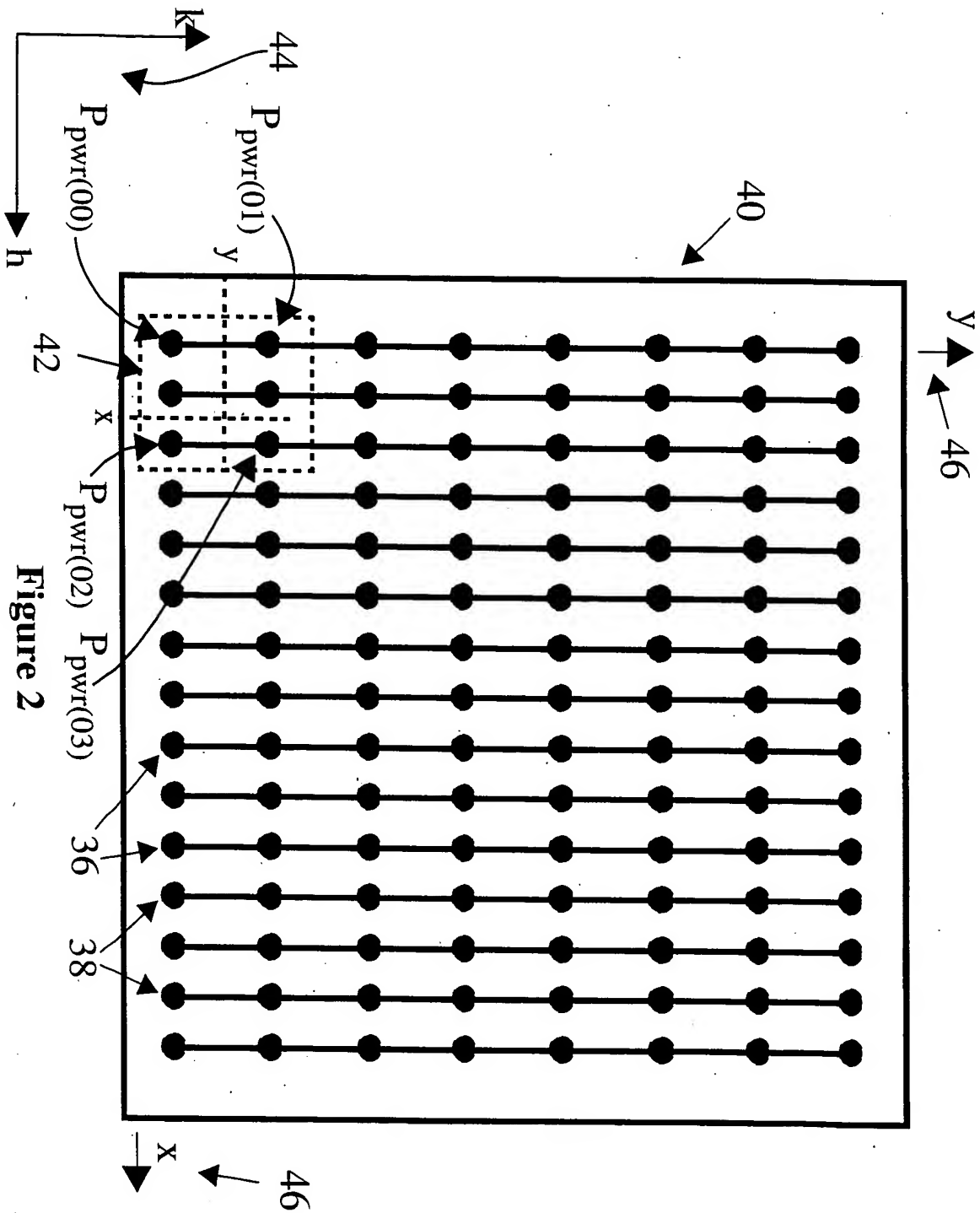


Figure 2

METHOD AND SYSTEM FOR IDENTIFYING AND  
LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

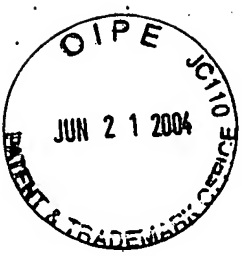
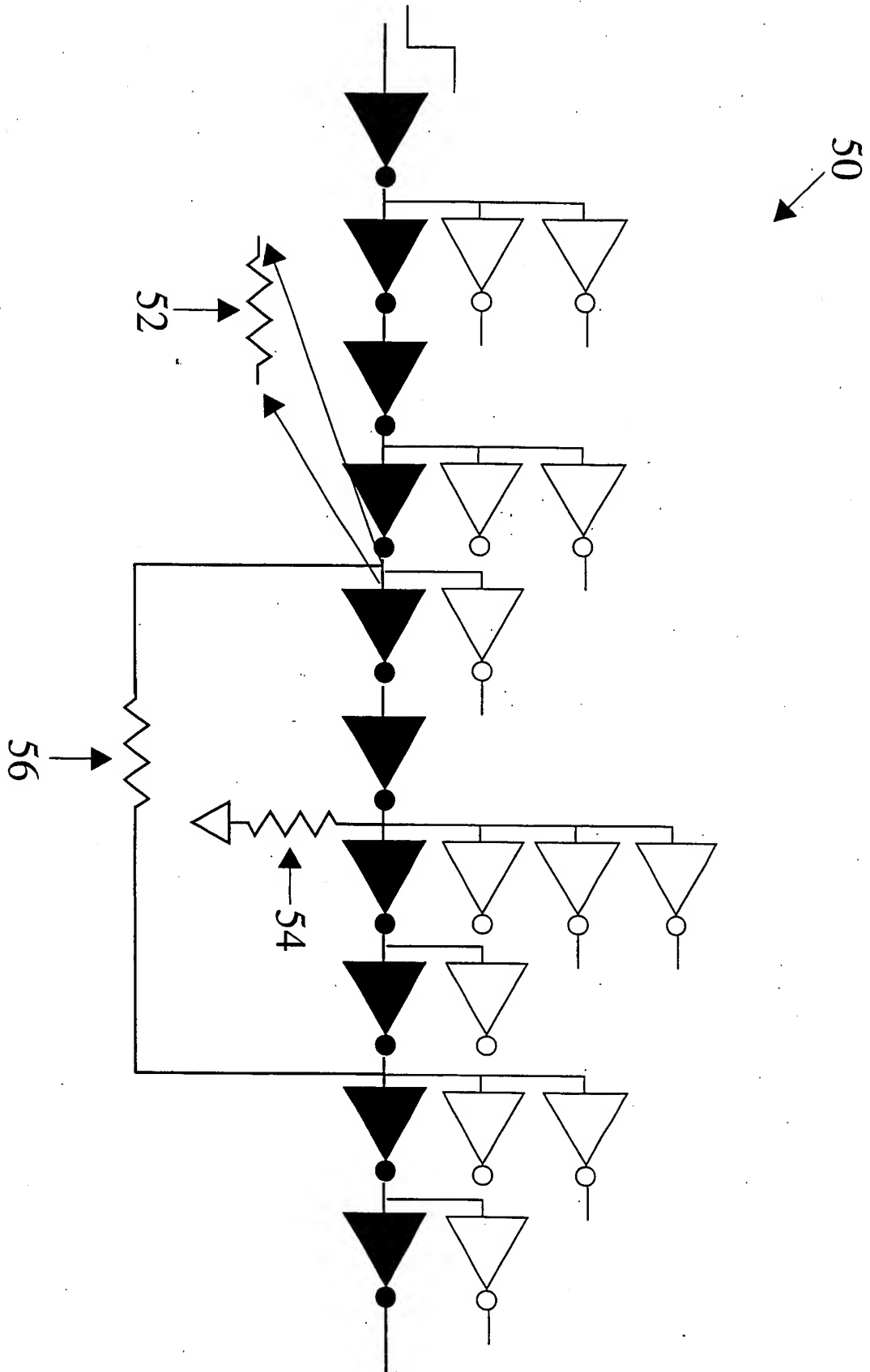
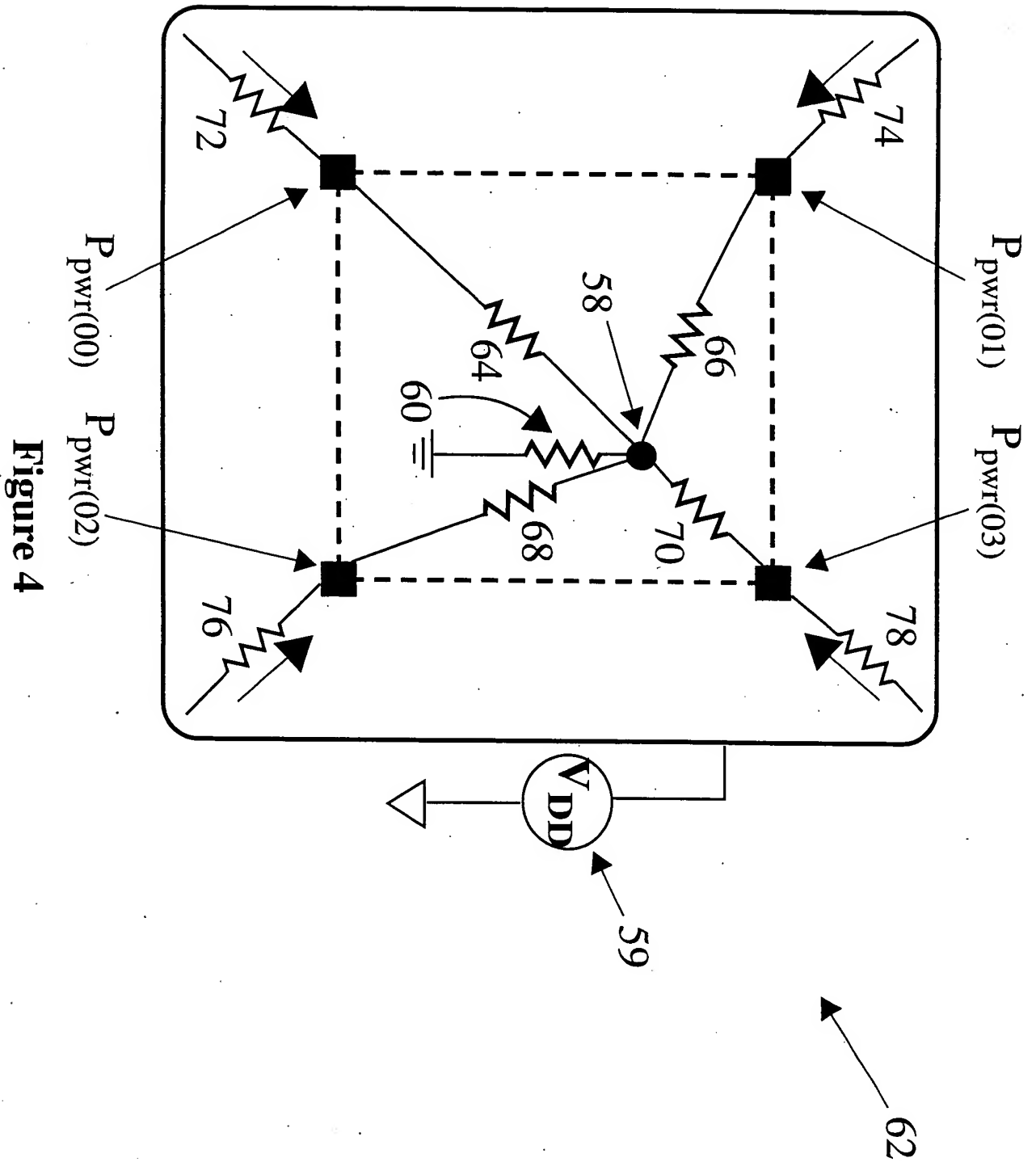
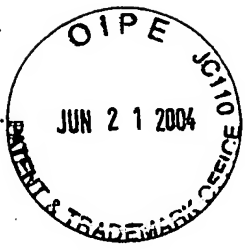


Figure 3





METHOD AND SYSTEM FOR IDENTIFYING AND  
LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

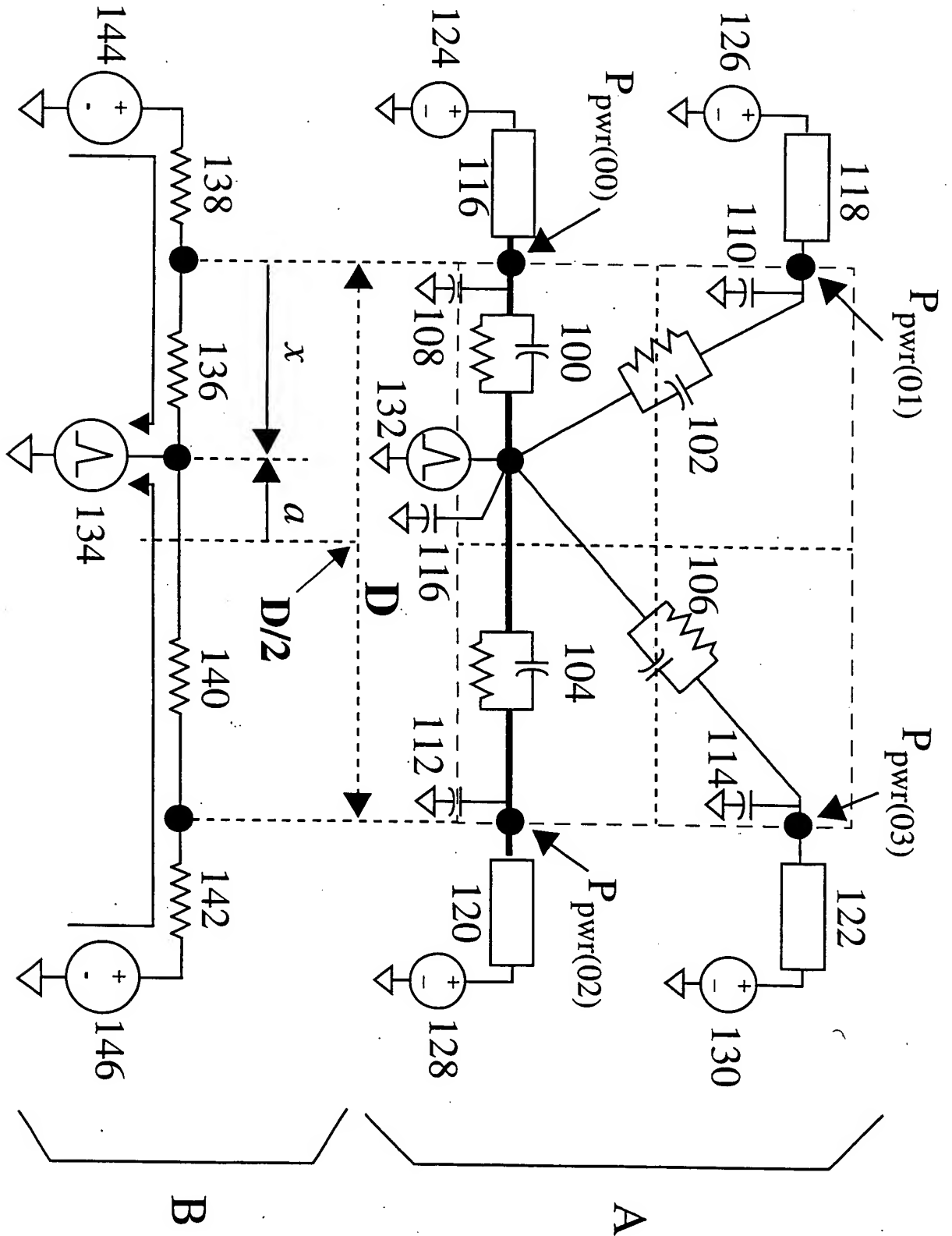


Figure 5

METHOD AND SYSTEM FOR IDENTIFYING AND  
LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

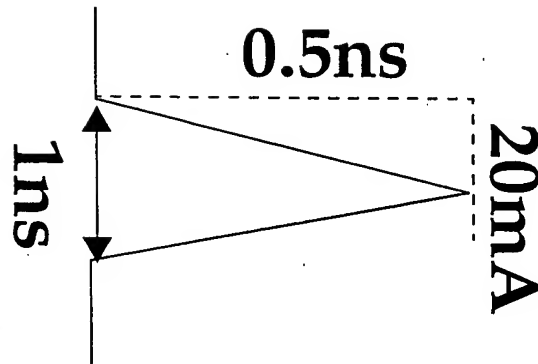


Figure 6

METHOD AND SYSTEM FOR IDENTIFYING AND  
LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

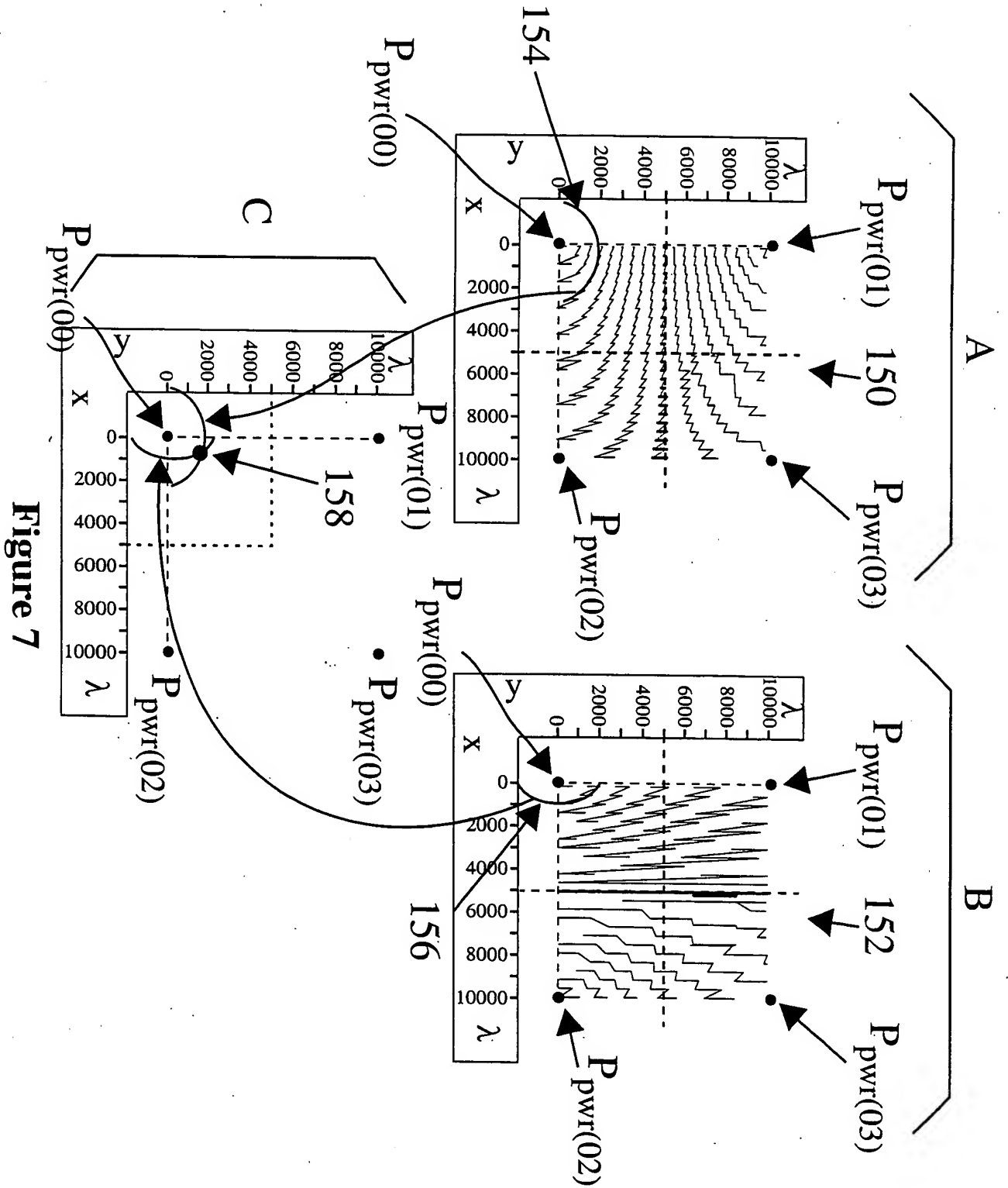


Figure 7

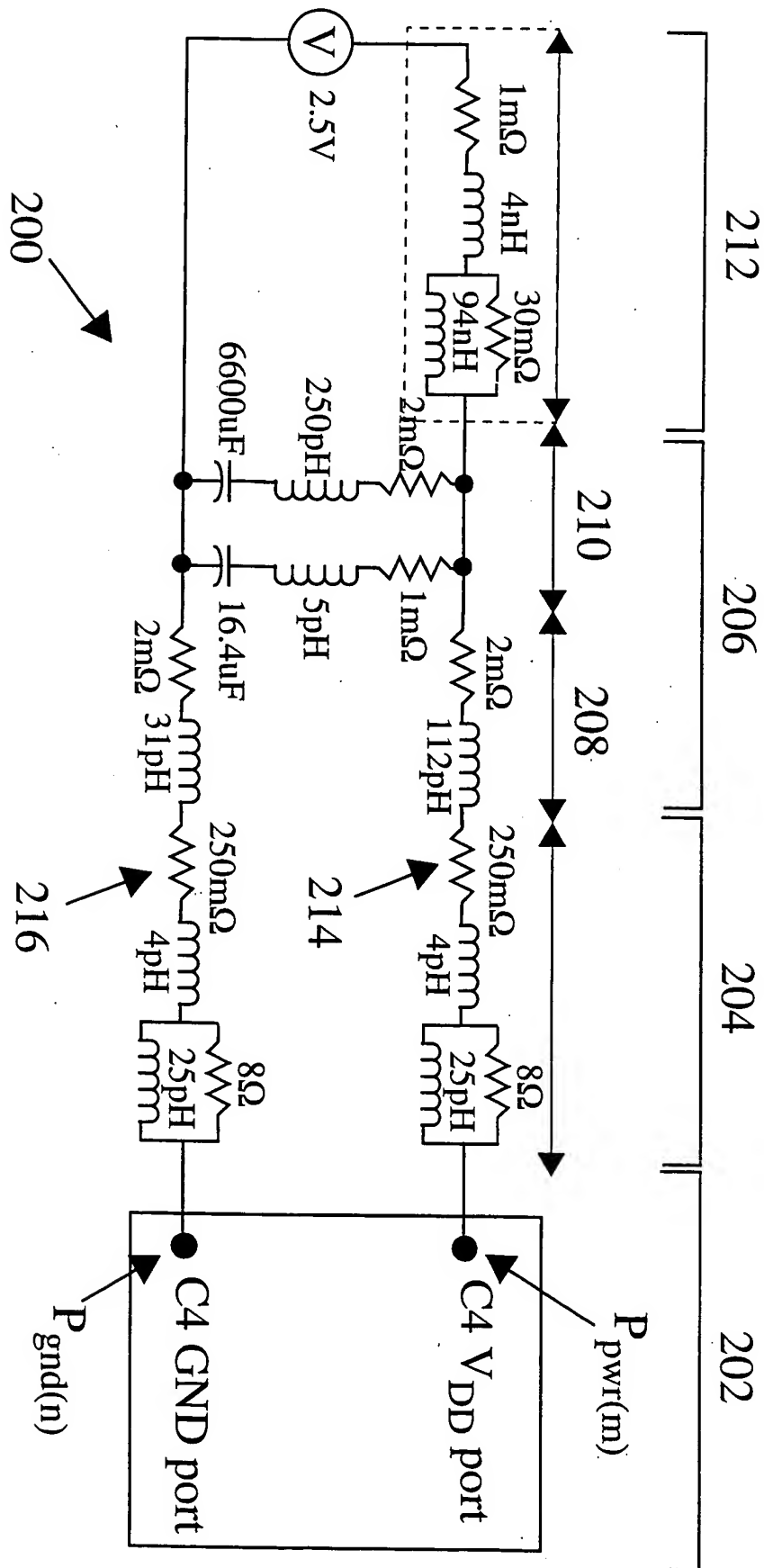
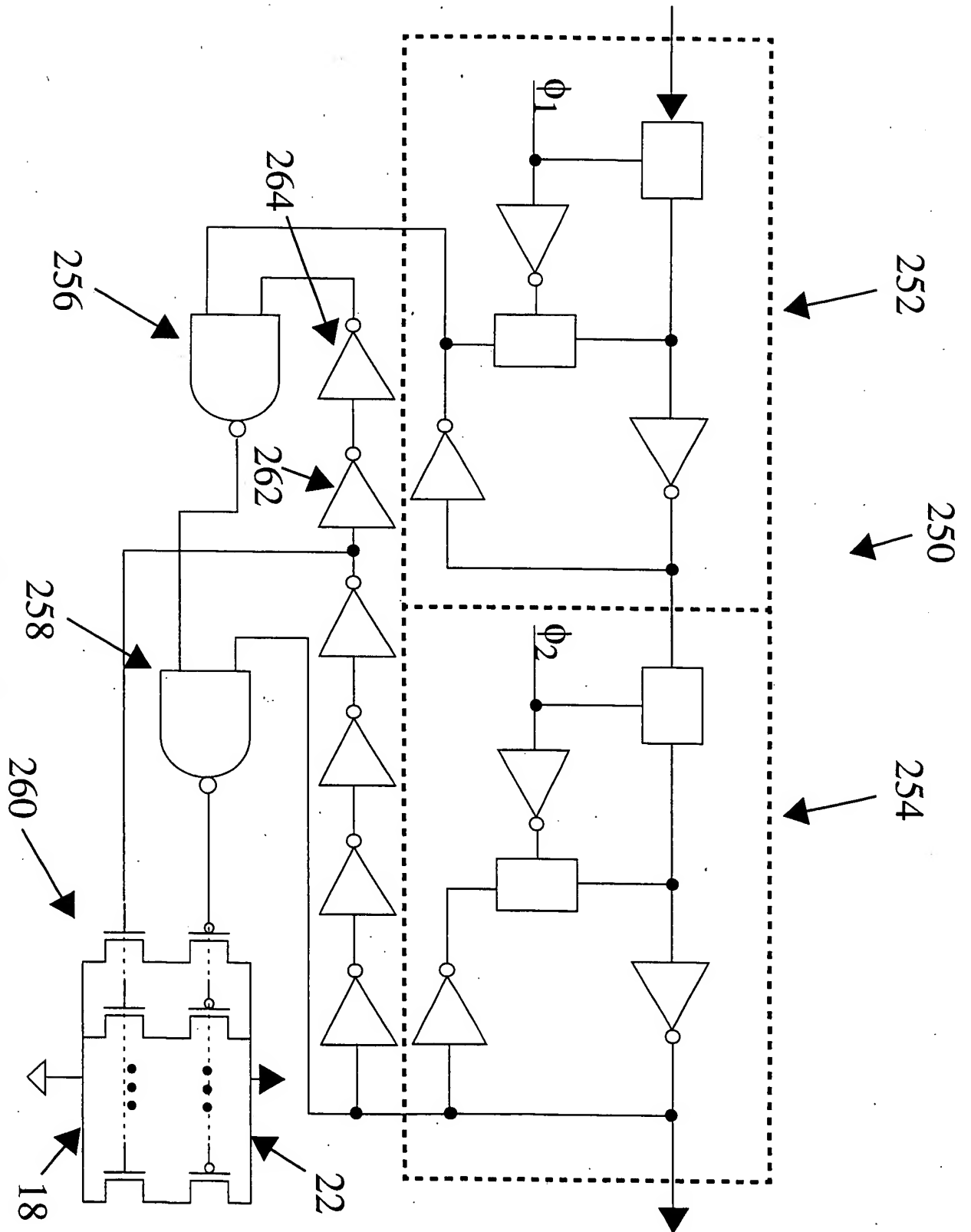


Figure 8





METHOD AND SYSTEM FOR IDENTIFYING AND  
LOCATING DEFECTS IN AN INTEGRATED CIRCUIT

Inventor: James Francis Plusquellic

Docket No.: P 1087.14002

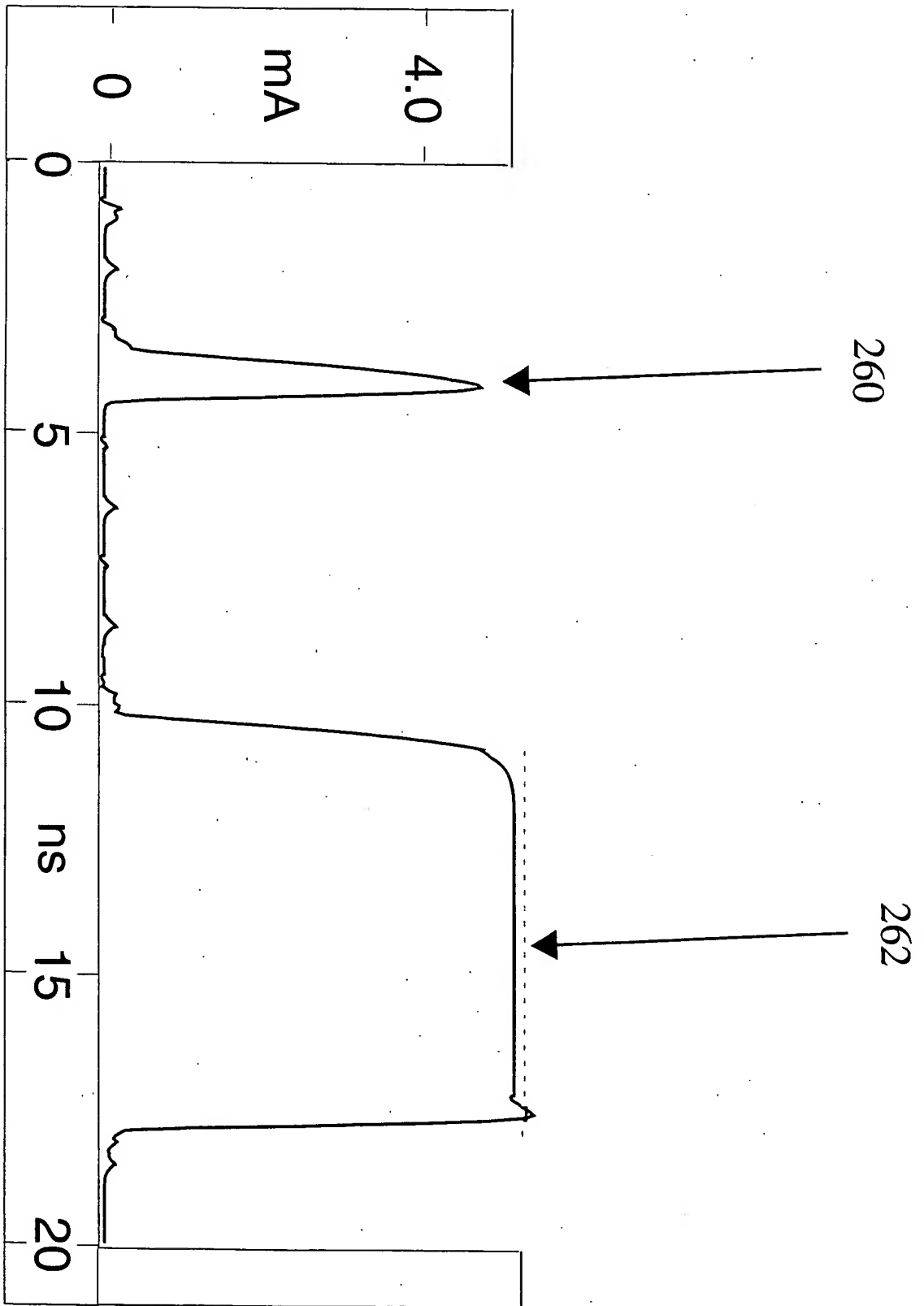


Figure 10

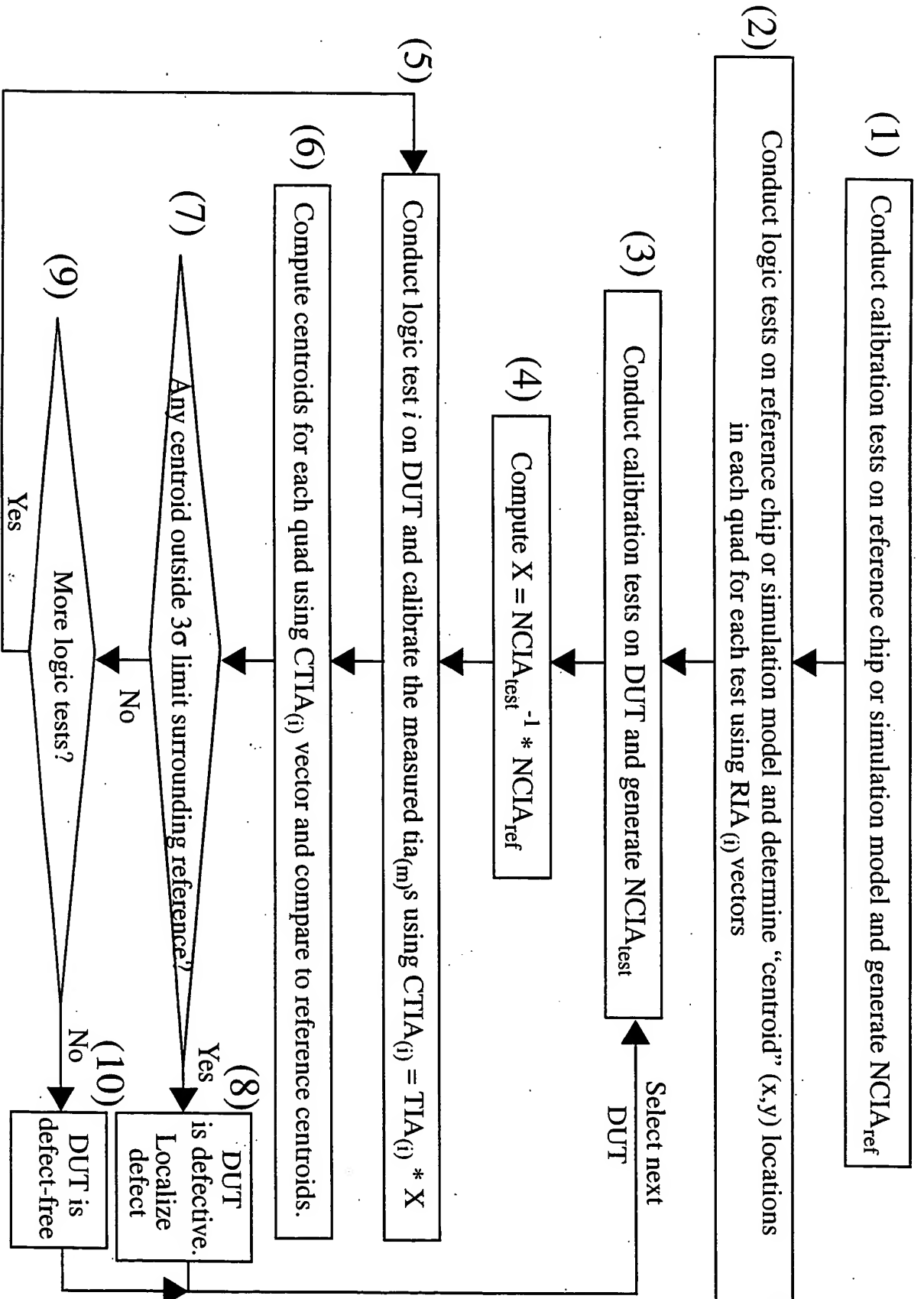


Figure 11

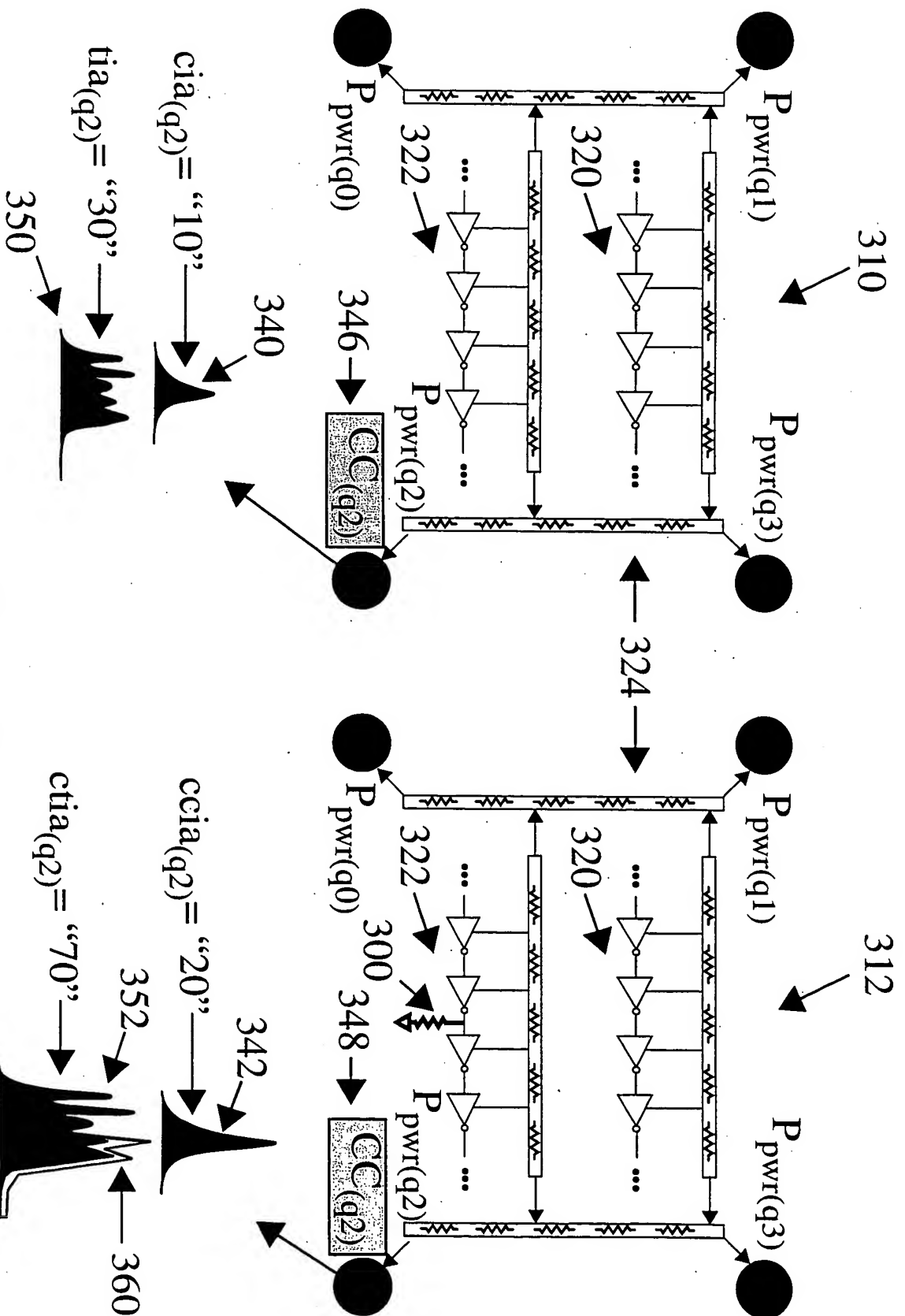


Figure 12